



**ALPHA & OMEGA**  
SEMICONDUCTOR

## AO3400A

### N-Channel Enhancement Mode Field Effect Transistor



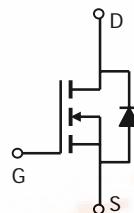
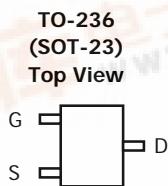
#### General Description

The AO3400A uses advanced trench technology to provide excellent  $R_{DS(ON)}$  and low gate charge. This device is suitable for use as a load switch or in PWM applications. Standard Product AO3400A is Pb-free (meets ROHS & Sony 259 specifications).

#### Features

$V_{DS} (V) = 30V$   
 $I_D = 5.7A (V_{GS} = 10V)$   
 $R_{DS(ON)} < 26.5m\Omega (V_{GS} = 10V)$   
 $R_{DS(ON)} < 32m\Omega (V_{GS} = 4.5V)$   
 $R_{DS(ON)} < 48m\Omega (V_{GS} = 2.5V)$

*Rg,Ciss,Coss,Crss Tested*



#### Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	30	V
Gate-Source Voltage	$V_{GS}$	$\pm 12$	V
Continuous Drain Current <sup>A,F</sup>	$I_D$	5.7	A
		4.7	
Pulsed Drain Current <sup>B</sup>	$I_{DM}$	25	A
Power Dissipation	$P_D$	1.4	W
		0.9	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

#### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	70	90	°C/W
Maximum Junction-to-Ambient <sup>A</sup>		100	125	°C/W
Maximum Junction-to-Lead <sup>C</sup>	$R_{\theta JL}$	63	80	°C/W

**AO3400A**
**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	30			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=30\text{V}, V_{GS}=0\text{V}$	$T_J=125^\circ\text{C}$	1	5	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 12\text{V}$			100	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	0.7	1	1.5	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=4.5\text{V}, V_{DS}=5\text{V}$	25			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=5.7\text{A}$		22	26.5	$\text{m}\Omega$
		$T_J=125^\circ\text{C}$	31	38		
				25.4	32	
		$V_{GS}=4.5\text{V}, I_D=5\text{A}$		34	48	
		$V_{GS}=2.5\text{V}, I_D=3\text{A}$				
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=5.7\text{A}$		26		S
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.72	1.0	V
$I_S$	Maximum Body-Diode Continuous Current				2.0	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		900	1100	pF
$C_{\text{oss}}$	Output Capacitance			88		pF
$C_{\text{rss}}$	Reverse Transfer Capacitance			65		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		0.95	1.5	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g$	Total Gate Charge	$V_{GS}=4.5\text{V}, V_{DS}=15\text{V}, I_D=5.7\text{A}$		10	13	nC
$Q_{\text{gs}}$	Gate Source Charge			1.8		nC
$Q_{\text{gd}}$	Gate Drain Charge			3.75		nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=2.6\Omega, R_{\text{GEN}}=3\Omega$		3.2		ns
$t_r$	Turn-On Rise Time			3.5		ns
$t_{\text{D(off)}}$	Turn-Off Delay Time			21.5		ns
$t_f$	Turn-Off Fall Time			2.7		ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$IF=5.7\text{A}, dI/dt=100\text{A/us}$		16.8	20	ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$IF=5.7\text{A}, dI/dt=100\text{A/us}$		8		nC

A: The value of  $R_{\theta JA}$  is measured with the device mounted on 1in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design.

B: Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{C}$ .

C. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to lead  $R_{\theta JL}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using <300 us pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

F: The current rating is based on the  $t \leq 10\text{s}$  thermal resistance rating.

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## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

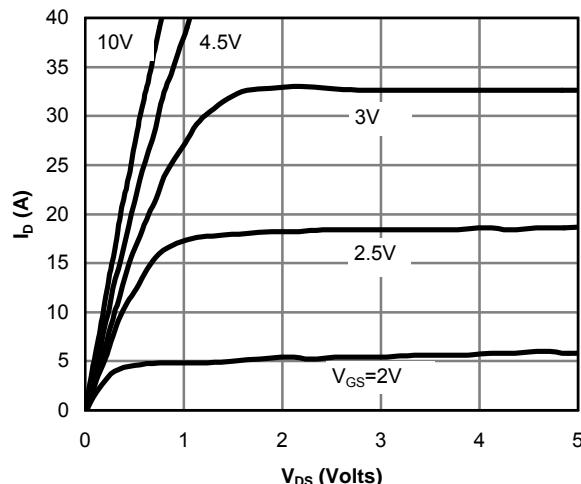


Figure 1: On-Region Characteristics

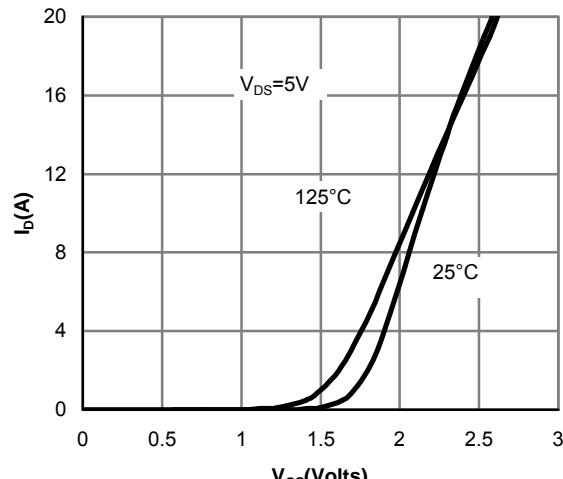


Figure 2: Transfer Characteristics

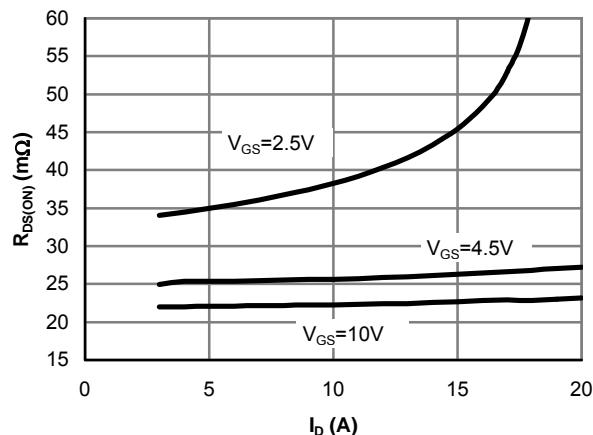


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

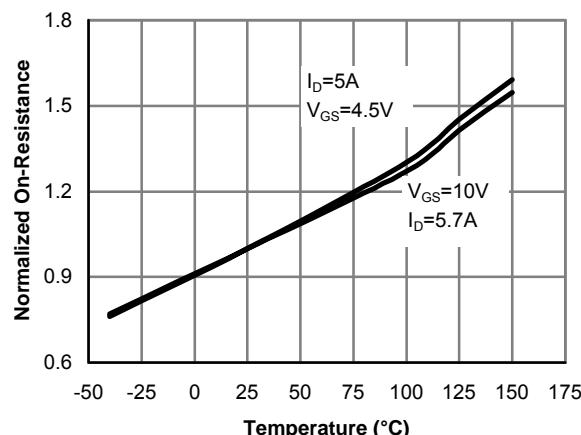


Figure 4: On-Resistance vs. Junction Temperature

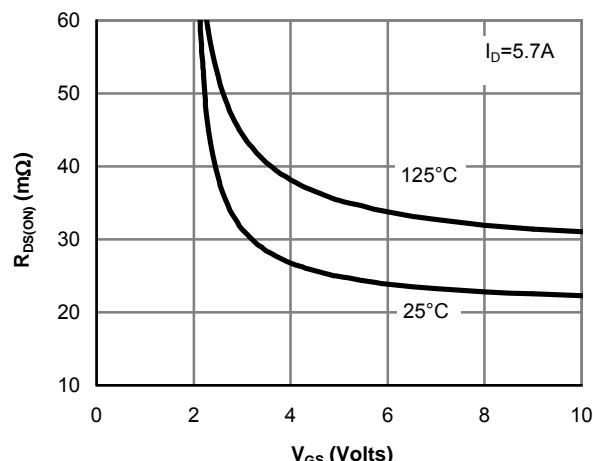


Figure 5: On-Resistance vs. Gate-Source Voltage

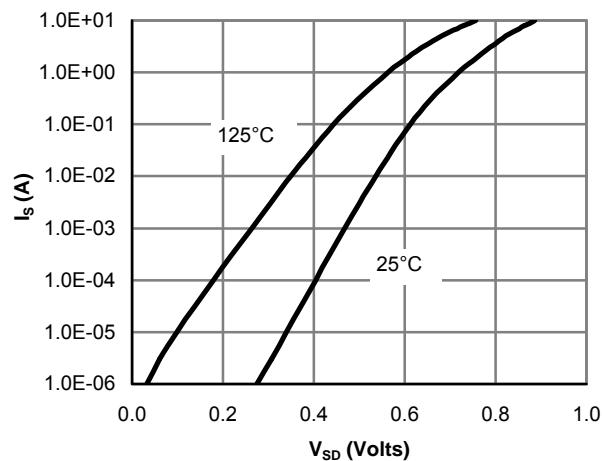


Figure 6: Body-Diode Characteristics

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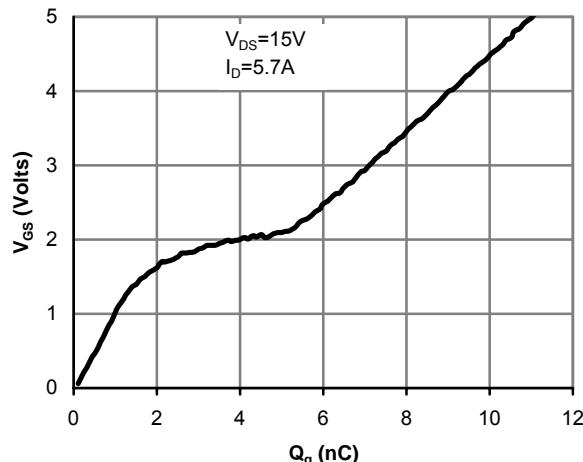


Figure 7: Gate-Charge Characteristics

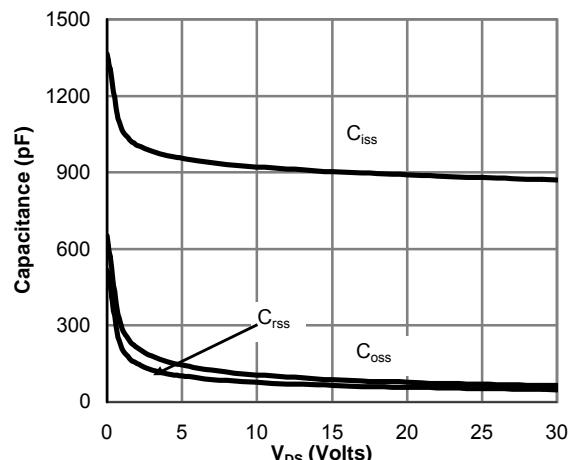


Figure 8: Capacitance Characteristics

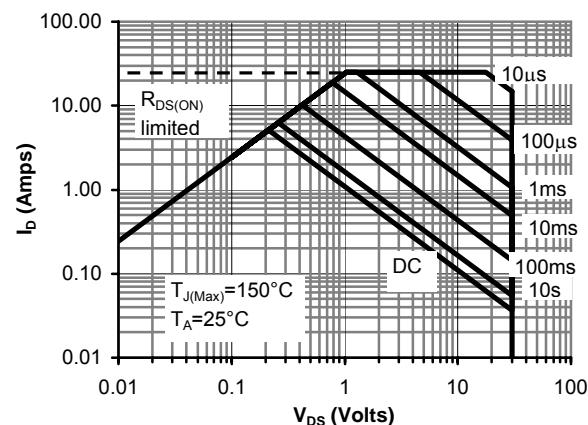


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

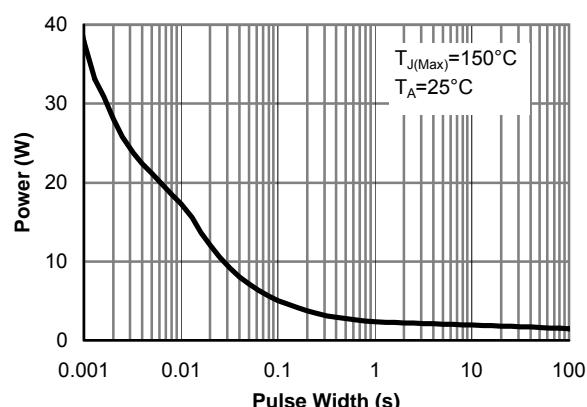


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

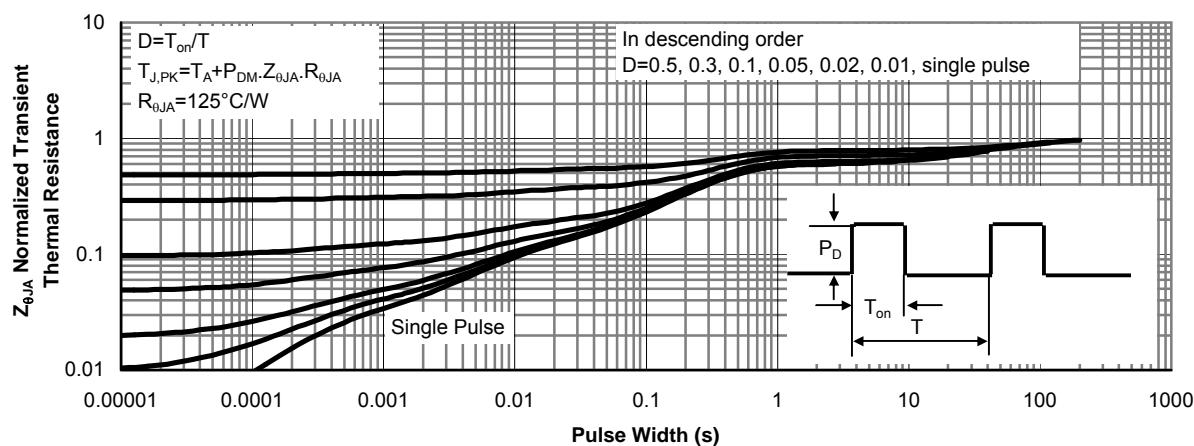


Figure 11: Normalized Maximum Transient Thermal Impedance